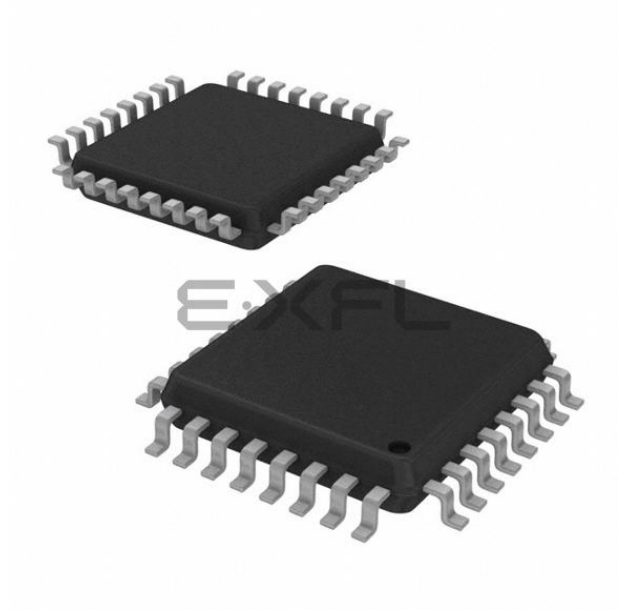

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What is "Embedded - Microcontrollers"?

"Embedded - Microcontrollers" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "Embedded - Microcontrollers"

Details	
Product Status	Active
Core Processor	ARM® Cortex®-M0
Core Size	32-Bit Single-Core
Speed	48MHz
Connectivity	I²C, IrDA, LINbus, SPI, UART/USART
Peripherals	DMA, I²S, POR, PWM, WDT
Number of I/O	25
Program Memory Size	32KB (32K x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	4K x 8
Voltage - Supply (Vcc/Vdd)	2V ~ 3.6V
Data Converters	A/D 13x12b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 105°C (TA)
Mounting Type	Surface Mount
Package / Case	32-LQFP
Supplier Device Package	32-LQFP (7x7)
Purchase URL	https://www.e-xfl.com/product-detail/stmicroelectronics/stm32f031k6t7

List of tables

In Standby mode, it is put in power down mode. In this mode, the regulator output is in high impedance and the kernel circuitry is powered down, inducing zero consumption (but the contents of the registers and SRAM are lost).

3.5.4 Low-power modes

The STM32F031x4/x6 microcontrollers support three low-power modes to achieve the best compromise between low power consumption, short startup time and available wakeup sources:

- **Sleep mode**

  In Sleep mode, only the CPU is stopped. All peripherals continue to operate and can wake up the CPU when an interrupt/event occurs.

- **Stop mode**

  Stop mode achieves very low power consumption while retaining the content of SRAM and registers. All clocks in the 1.8 V domain are stopped, the PLL, the HSI RC and the HSE crystal oscillators are disabled. The voltage regulator can also be put either in normal or in low power mode.

  The device can be woken up from Stop mode by any of the EXTI lines. The EXTI line source can be one of the 16 external lines, the PVD output, RTC, I2C1 or USART1.

  USART1 and I2C1 peripherals can be configured to enable the HSI RC oscillator so as to get clock for processing incoming data. If this is used when the voltage regulator is put in low power mode, the regulator is first switched to normal mode before the clock is provided to the given peripheral.

- **Standby mode**

  The Standby mode is used to achieve the lowest power consumption. The internal voltage regulator is switched off so that the entire 1.8 V domain is powered off. The PLL, the HSI RC and the HSE crystal oscillators are also switched off. After entering Standby mode, SRAM and register contents are lost except for registers in the RTC domain and Standby circuitry.

  The device exits Standby mode when an external reset (NRST pin), an IWDG reset, a rising edge on the WKUP pins, or an RTC event occurs.

Note: The RTC, the IWDG, and the corresponding clock sources are not stopped by entering Stop or Standby mode.

3.6 Clocks and startup

System clock selection is performed on startup, however the internal RC 8 MHz oscillator is selected as default CPU clock on reset. An external 4-32 MHz clock can be selected, in which case it is monitored for failure. If failure is detected, the system automatically switches back to the internal RC oscillator. A software interrupt is generated if enabled. Similarly, full interrupt management of the PLL clock entry is available when necessary (for example on failure of an indirectly used external crystal, resonator or oscillator).

Several prescalers allow the application to configure the frequency of the AHB and the APB domains. The maximum frequency of the AHB and the APB domains is 48 MHz.

An analog watchdog feature allows very precise monitoring of the converted voltage of one, some or all selected channels. An interrupt is generated when the converted voltage is outside the programmed thresholds.

3.10.1 Temperature sensor

The temperature sensor (TS) generates a voltage V_{SENSE} that varies linearly with temperature.

The temperature sensor is internally connected to the ADC_IN16 input channel which is used to convert the sensor output voltage into a digital value.

The sensor provides good linearity but it has to be calibrated to obtain good overall accuracy of the temperature measurement. As the offset of the temperature sensor varies from chip to chip due to process variation, the uncalibrated internal temperature sensor is suitable for applications that detect temperature changes only.

To improve the accuracy of the temperature sensor measurement, each device is individually factory-calibrated by ST. The temperature sensor factory calibration data are stored by ST in the system memory area, accessible in read-only mode.

Table 3. Temperature sensor calibration values

Calibration value name	Description	Memory address
TS_CAL1	TS ADC raw data acquired at a temperature of 30 °C (± 5 °C), V_{DDA}= 3.3 V (± 10 mV)	0x1FFF F7B8 - 0x1FFF F7B9
TS_CAL2	TS ADC raw data acquired at a temperature of 110 °C (± 5 °C), V_{DDA}= 3.3 V (± 10 mV)	0x1FFF F7C2 - 0x1FFF F7C3

3.10.2 Internal voltage reference (V_{REFINT})

The internal voltage reference (V_{REFINT}) provides a stable (bandgap) voltage output for the ADC. V_{REFINT} is internally connected to the ADC_IN17 input channel. The precise voltage of V_{REFINT} is individually measured for each part by ST during production test and stored in the system memory area. It is accessible in read-only mode.

Table 4. Internal voltage reference calibration values

Calibration value name	Description	Memory address
VREFINT_CAL	Raw data acquired at a temperature of 30 °C (± 5 °C), V_{DDA}= 3.3 V (± 10 mV)	0x1FFF F7BA - 0x1FFF F7BB

3.10.3 V_{BAT} battery voltage monitoring

This embedded hardware feature allows the application to measure the V_{BAT} battery voltage using the internal ADC channel ADC_IN18. As the V_{BAT} voltage may be higher than V_{DDA}, and thus outside the ADC input range, the V_{BAT} pin is internally connected to a bridge divider by 2. As a consequence, the converted digital value is half the V_{BAT} voltage.

Table 11. Pin definitions (continued)

Pin number						Pin name (function upon reset)	Pin type	I/O structure	Notes	Pin functions	
LQFP48	LQFP32	UFQFPN32	UFQFPN28	WLCSP25	TSSOP20					Alternate functions	Additional functions
30	19	19	19	C1	17	PA9	I/O	FTf	-	USART1_TX, TIM1_CH2, I2C1_SCL	-
31	20	20	20	B1	18	PA10	I/O	FTf	-	USART1_RX, TIM1_CH3, TIM17_BKIN, I2C1_SDA	-
32	21	21	-	-	-	PA11	I/O	FT	-	USART1_CTS, TIM1_CH4, EVENTOUT	-
33	22	22	-	-	-	PA12	I/O	FT	-	USART1_RTS, TIM1_ETR, EVENTOUT	-
34	23	23	21	A1	19	PA13 (SWDIO)	I/O	FT	(5)	IR_OUT, SWDIO	-
35	-	-	-	-	-	PF6	I/O	FTf	-	I2C1_SCL	-
36	-	-	-	-	-	PF7	I/O	FTf	-	I2C1_SDA	-
37	24	24	22	A2	20	PA14 (SWCLK)	I/O	FT	(5)	USART1_TX, SWCLK	-
38	25	25	23	-	-	PA15	I/O	FT	(6)	SPI1_NSS, I2S1_WS, TIM2_CH_ETR, EVENTOUT, USART1_RX	-
39	26	26	24	-	-	PB3	I/O	FT	(6)	SPI1_SCK, I2S1_CK, TIM2_CH2, EVENTOUT	-
40	27	27	25	-	-	PB4	I/O	FT	(6)	SPI1_MISO, I2S1_MCK, TIM3_CH1, EVENTOUT	-

Table 14. STM32F031x4/x6 peripheral register boundary addresses

Bus	Boundary address	Size	Peripheral
	0x4800 1800 - 0x5FFF FFFF	~384 MB	Reserved
AHB2	0x4800 1400 - 0x4800 17FF	1KB	GPIOF
	0x4800 0C00 - 0x4800 13FF	2KB	Reserved
	0x4800 0800 - 0x4800 0BFF	1KB	GPIOC
	0x4800 0400 - 0x4800 07FF	1KB	GPIOB
	0x4800 0000 - 0x4800 03FF	1KB	GPIOA
	0x4002 4400 - 0x47FF FFFF	~128 MB	Reserved
AHB1	0x4002 3400 - 0x4002 3FFF	3 KB	Reserved
	0x4002 3000 - 0x4002 33FF	1 KB	CRC
	0x4002 2400 - 0x4002 2FFF	3 KB	Reserved
	0x4002 2000 - 0x4002 23FF	1 KB	Flash memory interface
	0x4002 1400 - 0x4002 1FFF	3 KB	Reserved
	0x4002 1000 - 0x4002 13FF	1 KB	RCC
	0x4002 0400 - 0x4002 0FFF	3 KB	Reserved
	0x4002 0000 - 0x4002 03FF	1 KB	DMA
	0x4001 8000 - 0x4001 FFFF	32 KB	Reserved
APB	0x4001 5C00 - 0x4001 7FFF	9KB	Reserved
	0x4001 5800 - 0x4001 5BFF	1KB	DBGMCU
	0x4001 4C00 - 0x4001 57FF	3KB	Reserved
	0x4001 4800 - 0x4001 4BFF	1KB	TIM17
	0x4001 4400 - 0x4001 47FF	1KB	TIM16
	0x4001 3C00 - 0x4001 43FF	2KB	Reserved
	0x4001 3800 - 0x4001 3BFF	1KB	USART1
	0x4001 3400 - 0x4001 37FF	1KB	Reserved
	0x4001 3000 - 0x4001 33FF	1KB	SPI1/I2S1
	0x4001 2C00 - 0x4001 2FFF	1KB	TIM1
	0x4001 2800 - 0x4001 2BFF	1KB	Reserved
	0x4001 2400 - 0x4001 27FF	1KB	ADC
	0x4001 0800 - 0x4001 23FF	7KB	Reserved
	0x4001 0400 - 0x4001 07FF	1KB	EXTI
	0x4001 0000 - 0x4001 03FF	1KB	SYSCFG
	0x4000 8000 - 0x4000 FFFF	32 KB	Reserved

6.1.7 Current consumption measurement

Figure 13. Current consumption measurement scheme

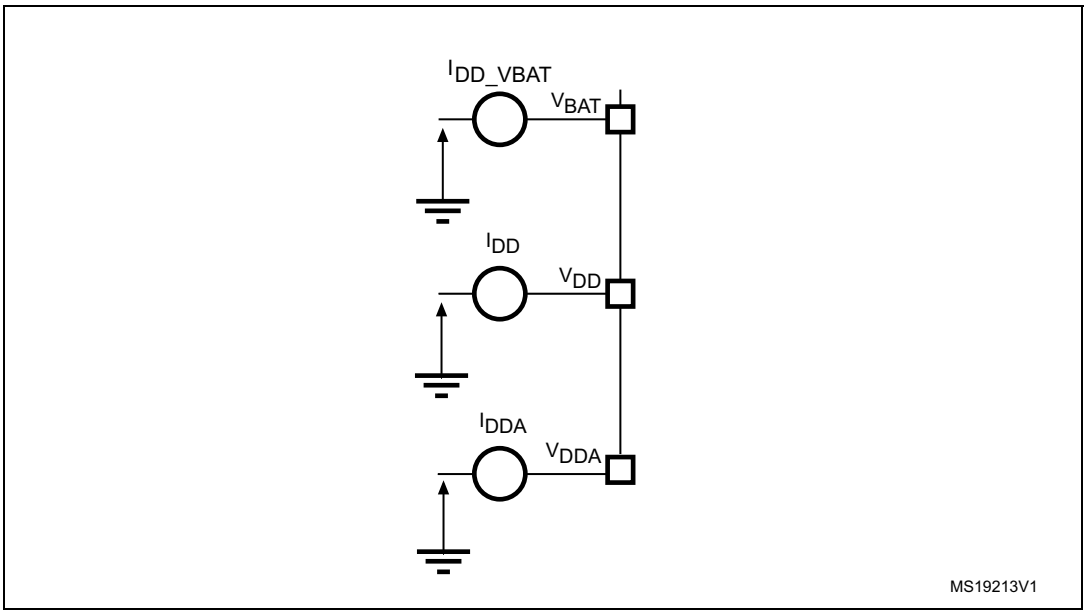


Table 23. Typical and maximum current consumption from V_{DD} at 3.6 V (continued)

Symbol	Parameter	Conditions	f_{HCLK}	All peripherals enabled				All peripherals disabled				Unit
				Typ	Max @ T_A(1)			Typ	Max @ T_A(1)			
					25 °C	85 °C	105 °C		25 °C	85 °C	105 °C	
I_{DD}	Supply current in Sleep mode	HSE bypass, PLL on	48 MHz	10.7	11.7(2)	11.9	12.5(2)	2.4	2.6(2)	2.7	2.9(2)	mA
			32 MHz	7.1	7.8	8.1	8.2	1.6	1.7	1.9	1.9	
			24 MHz	5.5	6.3	6.4	6.4	1.3	1.4	1.5	1.5	
		HSE bypass, PLL off	8 MHz	1.8	2.0	2.0	2.1	0.4	0.4	0.5	0.5	
			1 MHz	0.2	0.5	0.5	0.5	0.1	0.1	0.1	0.1	
		HSI clock, PLL on	48 MHz	10.8	11.9	12.1	12.6	2.4	2.7	2.7	2.9	
			32 MHz	7.3	8.0	8.4	8.5	1.7	1.9	1.9	2.0	
			24 MHz	5.5	6.2	6.5	6.5	1.3	1.5	1.5	1.6	
		HSI clock, PLL off	8 MHz	1.9	2.2	2.3	2.4	0.5	0.5	0.5	0.6	

1. Data based on characterization results, not tested in production unless otherwise specified.
2. Data based on characterization results and tested in production (using one common test limit for sum of I_{DD} and I_{DDA}).

Table 24. Typical and maximum current consumption from the V_{DDA} supply

Symbol	Parameter	Conditions (1)	f_{HCLK}	V_{DDA} = 2.4 V				V_{DDA} = 3.6 V				Unit
				Typ	Max @ T_A(2)			Typ	Max @ T_A(2)			
					25 °C	85 °C	105 °C		25 °C	85 °C	105 °C	
I_{DDA}	Supply current in Run or Sleep mode, code executing from Flash memory or RAM	HSE bypass, PLL on	48 MHz	150	170(3)	178	182(3)	164	183(3)	195	198(3)	µA
			32 MHz	104	121	126	128	113	129	135	138	
			24 MHz	82	96	100	103	88	102	106	108	
		HSE bypass, PLL off	8 MHz	2.0	2.7	3.1	3.3	3.5	3.8	4.1	4.4	
			1 MHz	2.0	2.7	3.1	3.3	3.5	3.8	4.1	4.4	
		HSI clock, PLL on	48 MHz	220	240	248	252	244	263	275	278	
			32 MHz	174	191	196	198	193	209	215	218	
			24 MHz	152	167	173	174	168	183	190	192	
		HSI clock, PLL off	8 MHz	72	79	82	83	83.5	91	94	95	

1. Current consumption from the V_{DDA} supply is independent of whether the digital peripherals are enabled or disabled, being in Run or Sleep mode or executing from Flash memory or RAM. Furthermore, when the PLL is off, I_{DDA} is independent of clock frequencies.
2. Data based on characterization results, not tested in production unless otherwise specified.
3. Data based on characterization results and tested in production (using one common test limit for sum of I_{DD} and I_{DDA}).

Table 26. Typical and maximum current consumption from the V_{BAT} supply

Symbol	Parameter	Conditions	Typ @ V_{BAT}						Max(1)			Unit
			1.65 V	1.8 V	2.4 V	2.7 V	3.3 V	3.6 V	T_A = 25 °C	T_A = 85 °C	T_A = 105 °C	
I_{DD_VBAT}	RTC domain supply current	LSE & RTC ON; “Xtal mode”: lower driving capability; LSEDRV[1:0] = '00'	0.5	0.5	0.6	0.7	0.8	0.9	1.0	1.3	1.7	µA
		LSE & RTC ON; “Xtal mode” higher driving capability; LSEDRV[1:0] = '11'	0.8	0.8	0.9	1.0	1.1	1.2	1.3	1.6	2.1	

1. Data based on characterization results, not tested in production.

Typical current consumption

The MCU is placed under the following conditions:

- $V_{DD} = V_{DDA} = 3.3$ V
- All I/O pins are in analog input configuration
- The Flash memory access time is adjusted to f_{HCLK} frequency:
  - 0 wait state and Prefetch OFF from 0 to 24 MHz
  - 1 wait state and Prefetch ON above 24 MHz
- When the peripherals are enabled, $f_{PCLK} = f_{HCLK}$
- PLL is used for frequencies greater than 8 MHz
- AHB prescaler of 2, 4, 8 and 16 is used for the frequencies 4 MHz, 2 MHz, 1 MHz and 500 kHz respectively

trigger circuits used to discriminate the input value. Unless this specific configuration is required by the application, this supply current consumption can be avoided by configuring these I/Os in analog mode. This is notably the case of ADC input pins which should be configured as analog inputs.

Caution: Any floating input pin can also settle to an intermediate voltage level or switch inadvertently, as a result of external electromagnetic noise. To avoid current consumption related to floating pins, they must either be configured in analog mode, or forced internally to a definite digital value. This can be done either by using pull-up/down resistors or by configuring the pins in output mode.

I/O dynamic current consumption

In addition to the internal peripheral current consumption measured previously (see *Table 29: Peripheral current consumption*), the I/Os used by an application also contribute to the current consumption. When an I/O pin switches, it uses the current from the I/O supply voltage to supply the I/O pin circuitry and to charge/discharge the capacitive load (internal or external) connected to the pin:

$$I_{SW} = V_{DDIOx} \times f_{SW} \times C$$

where

I_{SW} is the current sunk by a switching I/O to charge/discharge the capacitive load

V_{DDIOx} is the I/O supply voltage

f_{SW} is the I/O switching frequency

C is the total capacitance seen by the I/O pin: $C = C_{INT} + C_{EXT} + C_S$

C_S is the PCB board capacitance including the pad pin.

The test pin is configured in push-pull output mode and is toggled by software at a fixed frequency.

Low-speed internal (LSI) RC oscillator

Table 37. LSI oscillator characteristics(1)

Symbol	Parameter	Min	Typ	Max	Unit
f_{LSI}	Frequency	30	40	50	kHz
$t_{su(LSI)}$(2)	LSI oscillator startup time	-	-	85	µs
$I_{DDA(LSI)}$(2)	LSI oscillator power consumption	-	0.75	1.2	µA

1. V_{DDA} = 3.3 V, T_A = –40 to 105 °C unless otherwise specified.
2. Guaranteed by design, not tested in production.

6.3.9 PLL characteristics

The parameters given in *Table 38* are derived from tests performed under ambient temperature and supply voltage conditions summarized in *Table 18: General operating conditions*.

Table 38. PLL characteristics

Symbol	Parameter	Value			Unit
		Min	Typ	Max	
f_{PLL_IN}	PLL input clock(1)	1(2)	8.0	24(2)	MHz
	PLL input clock duty cycle	40(2)	-	60(2)	%
f_{PLL_OUT}	PLL multiplier output clock	16(2)	-	48	MHz
t_{LOCK}	PLL lock time	-	-	200(2)	µs
$Jitter_{PLL}$	Cycle-to-cycle jitter	-	-	300(2)	ps

1. Take care to use the appropriate multiplier factors to obtain PLL input clock values compatible with the range defined by f_{PLL_OUT}.
2. Guaranteed by design, not tested in production.

6.3.10 Memory characteristics

Flash memory

The characteristics are given at T_A = –40 to 105 °C unless otherwise specified.

Table 39. Flash memory characteristics

Symbol	Parameter	Conditions	Min	Typ	Max(1)	Unit
t_{prog}	16-bit programming time	T_A = - 40 to +105 °C	40	53.5	60	µs
t_{ERASE}	Page (1 KB) erase time	T_A = - 40 to +105 °C	20	-	40	ms
t_{ME}	Mass erase time	T_A = - 40 to +105 °C	20	-	40	ms
I_{DD}	Supply current	Write mode	-	-	10	mA
		Erase mode	-	-	12	mA

1. Guaranteed by design, not tested in production.

Software recommendations

The software flowchart must include the management of runaway conditions such as:

- Corrupted program counter
- Unexpected reset
- Critical Data corruption (for example control registers)

Prequalification trials

Most of the common failures (unexpected reset and program counter corruption) can be reproduced by manually forcing a low state on the NRST pin or the Oscillator pins for 1 second.

To complete these trials, ESD stress can be applied directly on the device, over the range of specification values. When unexpected behavior is detected, the software can be hardened to prevent unrecoverable errors occurring (see application note AN1015).

Electromagnetic Interference (EMI)

The electromagnetic field emitted by the device are monitored while a simple application is executed (toggling 2 LEDs through the I/O ports). This emission test is compliant with IEC 61967-2 standard which specifies the test board and the pin loading.

Table 42. EMI characteristics

Symbol	Parameter	Conditions	Monitored frequency band	Max vs. [f_{HSE}/f_{HCLK}]	Unit
				8/48 MHz	
S_{EMI}	Peak level	V_{DD} = 3.6 V, T_A = 25 °C, LQFP48 package compliant with IEC 61967-2	0.1 to 30 MHz	-11	dBµV
			30 to 130 MHz	21	
			130 MHz to 1 GHz	21	
			EMI Level	4	-

6.3.12 Electrical sensitivity characteristics

Based on three different tests (ESD, LU) using specific measurement methods, the device is stressed in order to determine its performance in terms of electrical sensitivity.

Electrostatic discharge (ESD)

Electrostatic discharges (a positive then a negative pulse separated by 1 second) are applied to the pins of each sample according to each pin combination. The sample size depends on the number of supply pins in the device (3 parts × (n+1) supply pins). This test conforms to the JESD22-A114/C101 standard.

Input/output AC characteristics

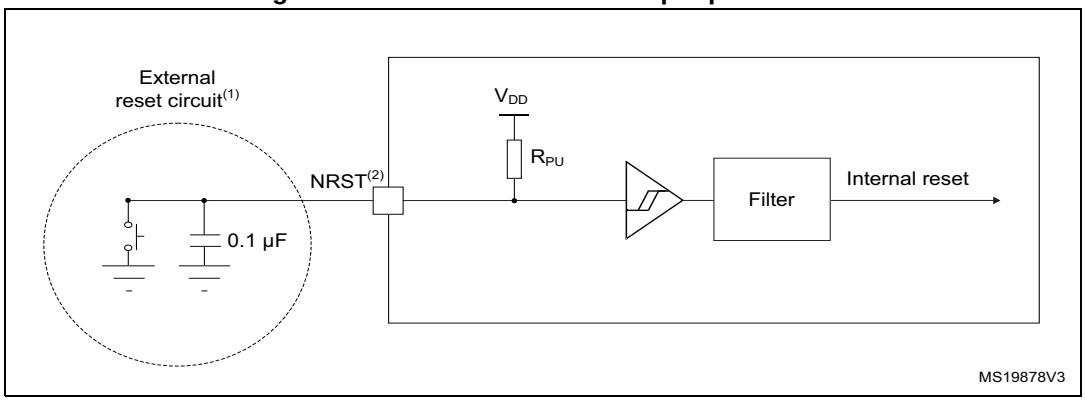
The definition and values of input/output AC characteristics are given in *Figure 22* and *Table 48*, respectively. Unless otherwise specified, the parameters given are derived from tests performed under the ambient temperature and supply voltage conditions summarized in *Table 18: General operating conditions*.

Table 48. I/O AC characteristics(1)(2)

OSPEEDRy [1:0] value(1)	Symbol	Parameter	Conditions	Min	Max	Unit
x0	$f_{max(IO)out}$	Maximum frequency(3)	C_L = 50 pF	-	2	MHz
	$t_{f(IO)out}$	Output fall time		-	125	ns
	$t_{r(IO)out}$	Output rise time		-	125	
01	$f_{max(IO)out}$	Maximum frequency(3)	C_L = 50 pF	-	10	MHz
	$t_{f(IO)out}$	Output fall time		-	25	ns
	$t_{r(IO)out}$	Output rise time		-	25	
11	$f_{max(IO)out}$	Maximum frequency(3)	C_L = 30 pF, $V_{DDIOx} \geq$ 2.7 V	-	50	MHz
			C_L = 50 pF, $V_{DDIOx} \geq$ 2.7 V	-	30	
			C_L = 50 pF, V_{DDIOx} < 2.7 V	-	20	
	$t_{f(IO)out}$	Output fall time	C_L = 30 pF, $V_{DDIOx} \geq$ 2.7 V	-	5	ns
			C_L = 50 pF, $V_{DDIOx} \geq$ 2.7 V	-	8	
			C_L = 50 pF, V_{DDIOx} < 2.7 V	-	12	
	$t_{r(IO)out}$	Output rise time	C_L = 30 pF, $V_{DDIOx} \geq$ 2.7 V	-	5	
			C_L = 50 pF, $V_{DDIOx} \geq$ 2.7 V	-	8	
			C_L = 50 pF, V_{DDIOx} < 2.7 V	-	12	
Fm+ configuration (4)	$f_{max(IO)out}$	Maximum frequency(3)	C_L = 50 pF	-	2	MHz
	$t_{f(IO)out}$	Output fall time		-	12	ns
	$t_{r(IO)out}$	Output rise time		-	34	
-	t_{EXTIpw}	Pulse width of external signals detected by the EXTI controller	-	10	-	ns

1. The I/O speed is configured using the OSPEEDRx[1:0] bits. Refer to the STM32F0xxxx RM0091 reference manual for a description of GPIO Port configuration register.
2. Guaranteed by design, not tested in production.
3. The maximum frequency is defined in *Figure 22*.
4. When Fm+ configuration is set, the I/O speed control is bypassed. Refer to the STM32F0xxxx reference manual RM0091 for a detailed description of Fm+ I/O configuration.

Figure 23. Recommended NRST pin protection



1. The external capacitor protects the device against parasitic resets.
2. The user must ensure that the level on the NRST pin can go below the $V_{IL(NRST)}$ max level specified in *Table 49: NRST pin characteristics*. Otherwise the reset will not be taken into account by the device.

6.3.16 12-bit ADC characteristics

Unless otherwise specified, the parameters given in *Table 50* are derived from tests performed under the conditions summarized in *Table 18: General operating conditions*.

Note: It is recommended to perform a calibration after each power-up.

Table 50. ADC characteristics

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
V_{DDA}	Analog supply voltage for ADC ON	-	2.4	-	3.6	V
$I_{DDA\ (ADC)}$	Current consumption of the ADC(1)	V_{DDA} = 3.3 V	-	0.9	-	mA
f_{ADC}	ADC clock frequency	-	0.6	-	14	MHz
f_S(2)	Sampling rate	12-bit resolution	0.043	-	1	MHz
f_{TRIG}(2)	External trigger frequency	f_{ADC} = 14 MHz, 12-bit resolution	-	-	823	kHz
		12-bit resolution	-	-	17	$1/f_{ADC}$
V_{AIN}	Conversion voltage range	-	0	-	V_{DDA}	V
R_{AIN}(2)	External input impedance	See *Equation 1* and *Table 51* for details	-	-	50	kΩ
R_{ADC}(2)	Sampling switch resistance	-	-	-	1	kΩ
C_{ADC}(2)	Internal sample and hold capacitor	-	-	-	8	pF
t_{CAL}(2)(3)	Calibration time	f_{ADC} = 14 MHz	5.9			µs
		-	83			$1/f_{ADC}$

6.3.17 Temperature sensor characteristics

Table 53. TS characteristics

Symbol	Parameter	Min	Typ	Max	Unit
T_L (1)	V_{SENSE} linearity with temperature	-	± 1	± 2	°C
Avg_Slope(1)	Average slope	4.0	4.3	4.6	mV/°C
V_{30}	Voltage at 30 °C (± 5 °C)(2)	1.34	1.43	1.52	V
t_{START} (1)	ADC_IN16 buffer startup time	-	-	10	µs
t_{S_temp} (1)	ADC sampling time when reading the temperature	4	-	-	µs

1. Guaranteed by design, not tested in production.
2. Measured at V_{DDA} = 3.3 V ± 10 mV. The V_{30} ADC conversion result is stored in the TS_CAL1 byte. Refer to *Table 3: Temperature sensor calibration values*.

6.3.18 V_{BAT} monitoring characteristics

Table 54. V_{BAT} monitoring characteristics

Symbol	Parameter	Min	Typ	Max	Unit
R	Resistor bridge for V_{BAT}	-	2 x 50	-	kΩ
Q	Ratio on V_{BAT} measurement	-	2	-	-
Er(1)	Error on Q	–1	-	+1	%
t_{S_vbat} (1)	ADC sampling time when reading the V_{BAT}	4	-	-	µs

1. Guaranteed by design, not tested in production.

6.3.19 Timer characteristics

The parameters given in the following tables are guaranteed by design.

Refer to *Section 6.3.14: I/O port characteristics* for details on the input/output alternate function characteristics (output compare, input capture, external clock, PWM output).

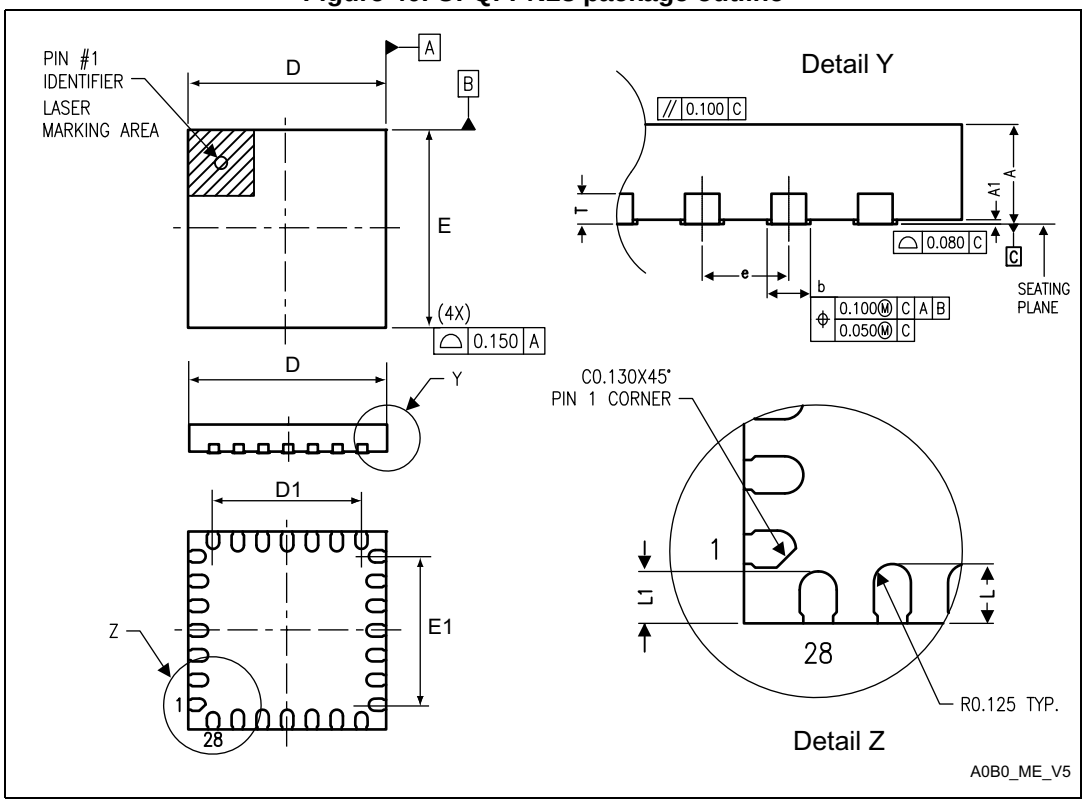
Table 55. TIMx characteristics

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
$t_{res(TIM)}$	Timer resolution time	-	-	1	-	$t_{TIMxCLK}$
		$f_{TIMxCLK}$ = 48 MHz	-	20.8	-	ns
f_{EXT}	Timer external clock frequency on CH1 to CH4	-	-	$f_{TIMxCLK}/2$	-	MHz
		$f_{TIMxCLK}$ = 48 MHz	-	24	-	MHz
t_{MAX_COUNT}	16-bit timer maximum period	-	-	2^{16}	-	$t_{TIMxCLK}$
		$f_{TIMxCLK}$ = 48 MHz	-	1365	-	µs
	32-bit counter maximum period	-	-	2^{32}	-	$t_{TIMxCLK}$
		$f_{TIMxCLK}$ = 48 MHz	-	89.48	-	s

7.4 UFQFPN28 package information

UFQFPN28 is a 28-lead, 4x4 mm, 0.5 mm pitch, ultra-thin fine-pitch quad flat package.

Figure 40. UFQFPN28 package outline



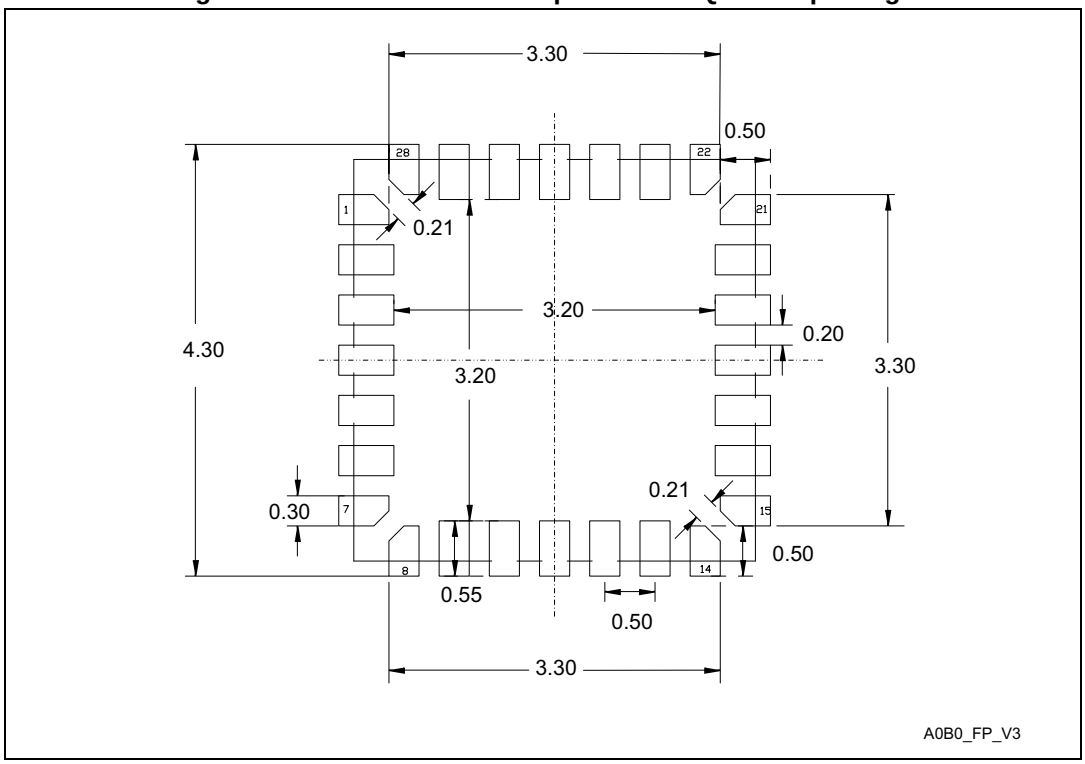
1. Drawing is not to scale.

Table 64. UFQFPN28 package mechanical data(1)

Symbol	millimeters			inches		
	Min	Typ	Max	Min	Typ	Max
A	0.500	0.550	0.600	0.0197	0.0217	0.0236
A1	-	0.000	0.050	-	0.0000	0.0020
D	3.900	4.000	4.100	0.1535	0.1575	0.1614
D1	2.900	3.000	3.100	0.1142	0.1181	0.1220
E	3.900	4.000	4.100	0.1535	0.1575	0.1614
E1	2.900	3.000	3.100	0.1142	0.1181	0.1220
L	0.300	0.400	0.500	0.0118	0.0157	0.0197
L1	0.250	0.350	0.450	0.0098	0.0138	0.0177
T	-	0.152	-	-	0.0060	-
b	0.200	0.250	0.300	0.0079	0.0098	0.0118
e	-	0.500	-	-	0.0197	-

1. Values in inches are converted from mm and rounded to 4 decimal digits.

Figure 41. Recommended footprint for UFQFPN28 package

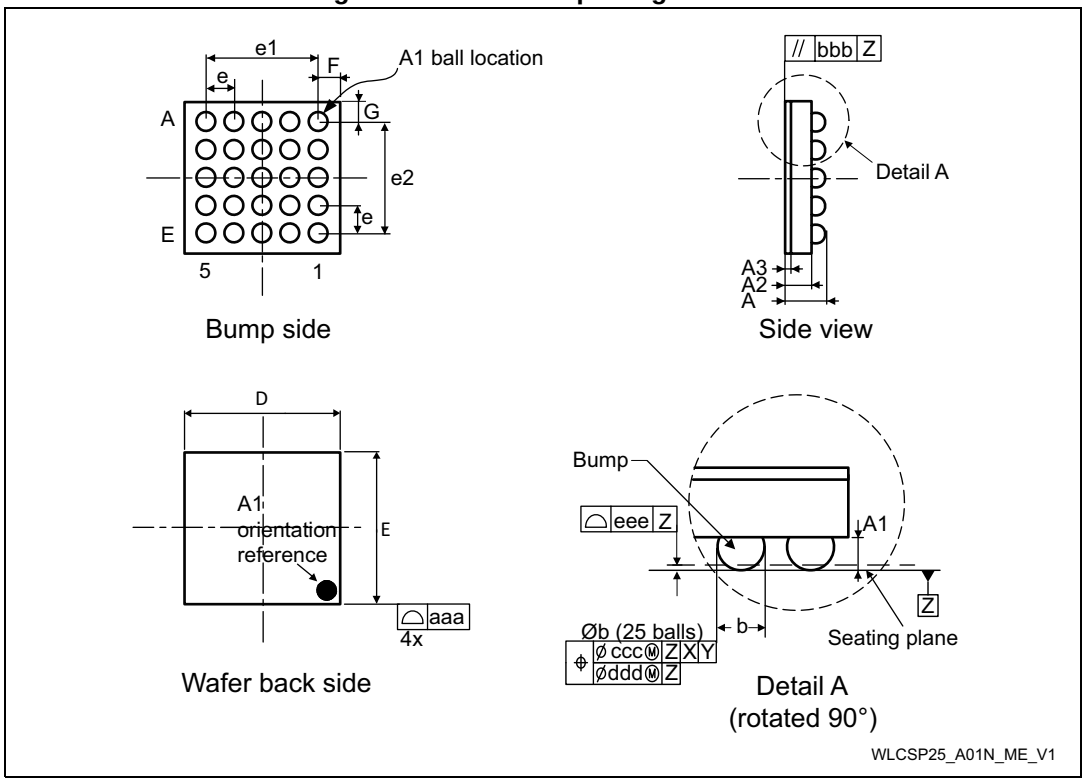


1. Dimensions are expressed in millimeters.

7.5 WLCSP25 package information

WLCSP25 is a 25-ball, 2.423 x 2.325 mm, 0.4 mm pitch wafer level chip scale package.

Figure 43. WLCSP25 package outline



1. Drawing is not to scale.

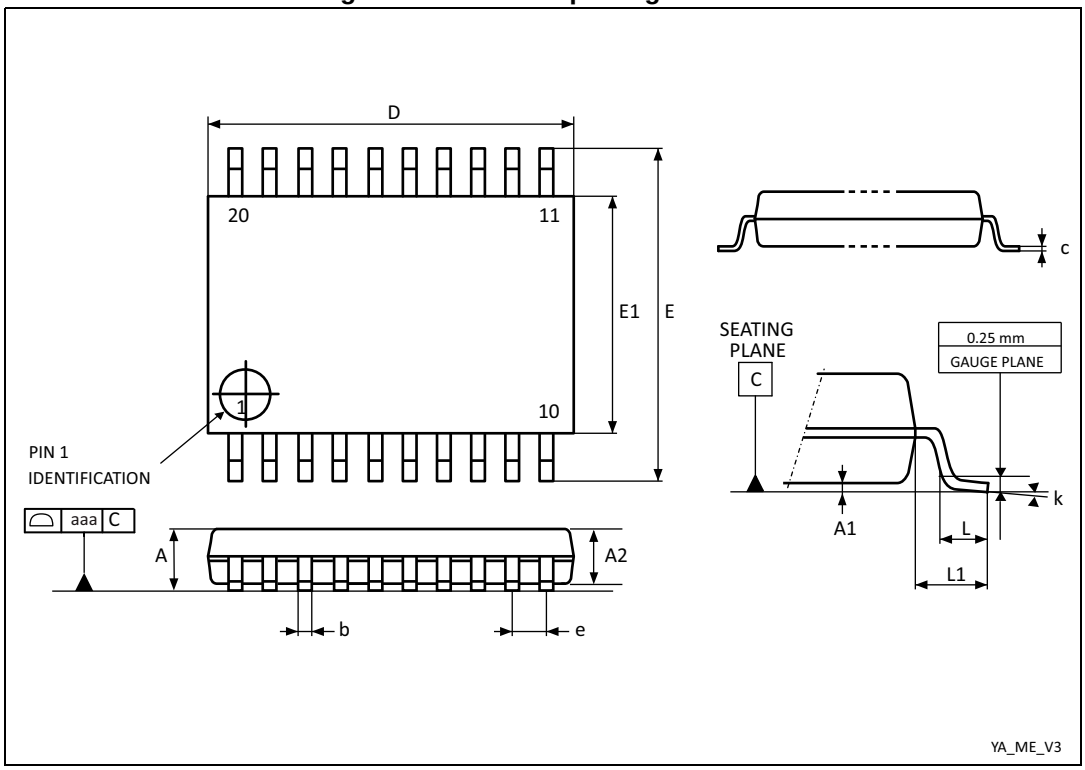
Table 65. WLCSP25 package mechanical data

Symbol	millimeters			inches(1)		
	Min	Typ	Max	Min	Typ	Max
A	0.525	0.555	0.585	0.0207	0.0219	0.0230
A1	-	0.175	-	-	0.0069	-
A2	-	0.380	-	-	0.0150	-
A3(2)	-	0.025	-	-	0.0010	-
b(3) (4)	0.220	0.250	0.280	0.0087	0.0098	0.0110
D	2.388	2.423	2.458	0.0940	0.0954	0.0968
E	2.29	2.325	2.36	0.0902	0.0915	0.0929
e	-	0.400	-	-	0.0157	-
e1	-	1.600	-	-	0.0630	-
e2	-	1.600	-	-	0.0630	-
F	-	0.4115	-	-	0.0162	-
G	-	0.3625	-	-	0.0143	-

7.6 TSSOP20 package information

TSSOP20 is a 20-lead thin shrink small-outline, 6.5 x 4.4 mm, 0.65 mm pitch, package.

Figure 46.TSSOP20 package outline



1. Drawing is not to scale.

Table 67. TSSOP20 package mechanical data

Symbol	millimeters			inches[1]		
	Min.	Typ.	Max.	Min.	Typ.	Max.
A	-	-	1.200	-	-	0.0472
A1	0.050	-	0.150	0.0020	-	0.0059
A2	0.800	1.000	1.050	0.0315	0.0394	0.0413
b	0.190	-	0.300	0.0075	-	0.0118
c	0.090	-	0.200	0.0035	-	0.0079
D[2]	6.400	6.500	6.600	0.2520	0.2559	0.2598
E	6.200	6.400	6.600	0.2441	0.2520	0.2598
E1[3]	4.300	4.400	4.500	0.1693	0.1732	0.1772
e	-	0.650	-	-	0.0256	-
L	0.450	0.600	0.750	0.0177	0.0236	0.0295
L1	-	1.000	-	-	0.0394	-

Table 70. Document revision history (continued)

Date	Revision	Changes
28-Aug-2015	3 (continued)	Added WLCSP25 package, updates in the following: – *Table 1: Device summary*, – *Section 2: Description*, – *Table 2: STM32F031x4/x6 family device features and peripheral counts*, – *Section 4: Pinouts and pin description*: addition of *Figure 7: WLCSP25 25-ball package ballout (bump side)* and update of *Table 11: Pin definitions*, – *Table 18: General operating conditions*, – *Section 7: Package information* with the addition of *Section 7.5: WLCSP25 package information*, – *Table 68: Package thermal characteristics*.
16-Dec-2015	4	**Cover page:** – number of timers added in the title – *Table 1: Device summary* - STM32F031x4 added ***Section 2: Description*:** – *Figure 1: Block diagram* updated ***Section 3: Functional overview*:** – *Figure 2: Clock tree* updated – *Section 3.5.4: Low-power modes* - added explicit inf. on peripherals configurable to operate with HSI – *Section 3.10.2: Internal voltage reference (V_{REFINT})* - removed information on comparators – *Section 3.11.2: General-purpose timers (TIM2, 3, 14, 16, 17)* - number of gen-purpose timers corrected – *Section Table 7.: STM32F031x4/x6 I^2C implementation* - added 20mA output drive current ***Section 4: Pinouts and pin description*:** – Package pinout figures updated (look and feel) – *Figure 7: WLCSP25 package pinout* - **now presented in top view** – *Table 11: Pin definitions* - notes 3 and 6 added ***Section 5: Memory mapping*:** – added information on memory mapping difference of STM32F031x4 from STM32F031x6 ***Section 6: Electrical characteristics*:** – *Table 22: Embedded internal reference voltage*: removed -40°-to-85° condition and associated note for V_{REFINT} – *Table 25* and *Table 26* values rounded to 1 decimal – *Table 46: I/O static characteristics* - removed note – *Table 50: ADC characteristics* - updated some parameter values, test conditions and added footnotes (3) and (4)